What is Claimed is:

1.   A light intensity distribution measuring method for measuring the light intensity distribution of a laser beam emitted by a semiconductor laser,
5   comprising the steps of:
measuring light intensities at a plurality of locations in a laser beam emitted by a semiconductor laser; and
applying their measurement results to a *t* distribution function to calculate the light intensity distribution.
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2.   The light intensity distribution measuring method as set forth in Claim 1, including the step of using nonlinear least squares for parameters of the *t* distribution function when said light intensity distribution is calculated.

15   3.   A light intensity distribution measuring device for measuring the light intensity distribution of a laser beam emitted by a semiconductor laser, comprising:
a light intensity detecting means that measures light intensities at a plurality of locations in a laser beam emitted by a semiconductor laser; and
20   data processing means for calculating the light intensity distribution by applying the measurement results obtained by said light intensity detecting means to a *t* distribution function.

4.   The light intensity distribution measuring device as set forth in
25   claim 3, wherein said data processing means uses nonlinear least squares for parameters of the *t* distribution function.